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| Notice of References Cited | Application/Control No. 09/737,471 | Applicant(s)/Patent Under Reexamination LEFEBVRE ET AL. | |
| | Examiner Clemence Han | Art Unit 2665 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| | A | US-6,765,904 | 07-2004 | Anandakumar et al. | 370/389 |
| | B | US-6,349,096 | 02-2002 | Liu et al. | 370/352 |
| | C | US-6,374,288 | 04-2002 | Bhagavath et al. | 709/203 |
| | D | US-6,798,744 | 09-2004 | Loewen et al. | 370/235 |
| | E | US-6,829,294 | 12-2004 | Sweitzer et al. | 375/225 |
| | F | US-6,542,465 | 04-2003 | Wang, Ray | 370/232 |
| | G | US-6,529,479 | 03-2003 | Suzuki, Hiroyuki | 370/236.1 |
| | H | US-6,640,239 | 10-2003 | Gidwani, Sanjay M. | 709/203 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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